



COMPLIANCE PROGRAM

TEST REPORT

USB 2.0 Test Report For Embedded Host Revision 2.0

Company Name: Freescale Semiconductor

VID (Dec or Hex): 15a2 The VID for the company who apply the USB-IF logo.

Model Name: MCIMX6SX SDB

Product Type: Embedded Host with Device Mode

Report Date: 2015/02/04

Test Result: **PASS**

Tester: Rex Xu

Authorized Signature: Howard Chang



Legal Disclaimer

1. TEST RESULT IS VALID ONLY TO THE ORIGINAL TESTED DEVICE MODEL. ALLION RESERVES THE RIGHT TO PROHIBIT OTHERS TO DISTORT, ISOLATE, FALSIFY, COPIED AND/OR BY ANY PROCESS TO CHANGE THE CONTENT OF THIS TEST REPORT UNLESS IT IS PRIOR APPROVED BY ALLION.



Company Information:

Company

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Product Information:

Information Obtained From Checklist or Vendor			
Input	Type	Purpose	Checklist Ref
Uses Micro-AB	<input type="checkbox"/>	Check this box for an EH which uses a Micro-AB receptacle instead of a Standard-A receptacle. It will be automatically selected for OTG devices.	P15a
Supports Sessions	<input type="checkbox"/>	Check this box if the OTG A-UUT or EH with Micro-AB receptacle does not keep V BUS enabled all the time that the ID pin is held low. Check this box for an EH with Standard-A receptacle which does not keep V BUS high all the time it is powered up. In either case it is assumed that SRP or ADP is available to detect the presence of a device.	PI10



Input	Type	Purpose	Checklist Ref
SRP as A-device	<input type="checkbox"/>	Check this box if the UUT, as an A-device, supports detecting, and acting on, an SRP pulse generated by a connected device.	PI13
HNP as A-device	<input type="checkbox"/>	Check this box if the UUT, as an A-device, supports HNP to enable the connected B-device to become host if it so requires.	PI13
HNP Polling as A-device	<input type="checkbox"/>	Check this box if the UUT, as an A-device, supports HNP polling. If it does it is allowed to remain as host, for as long as the other device does not set its Host Request Flag.	PI13
ADP as A-device	<input type="checkbox"/>	Check this box if the UUT, as an A-device, supports ADP probing to detect the presence or otherwise of a connected device.	PI13
SRP as B-device	<input type="checkbox"/>	Check this box if the UUT, as a B-device, supports generating an SRP pulse in order to start a session (cause the connected A-device to turn on V BUS).	PI20
HNP as B-device	<input type="checkbox"/>	Check this box if the UUT, as an B-device, supports HNP to allow it to become host if it so requires.	PI20
ADP as B-device	<input type="checkbox"/>	Check this box if the UUT, as an B-device, supports ADP sensing and probing to detect the presence or otherwise of a connected device.	PI20
FS Not Available	<input type="checkbox"/>	Check this box if UUT does not fully support full-speed operation. This is not permitted for an OTG device, but may be for an Embedded Host.	PI11, PI18



Input	Type	Purpose	Checklist Ref
I _{A_VBUS_RATED}	<u>500</u> mA	The rated output current of an A-device in mA units.	PI8
bMaxPower	<u>2</u> mA	bMaxPower (sic) is the highest current, in mA, declared in any of the device's Configuration Descriptors. This value ignores current drawn under the Battery Charging provisions.	PI17
TPWRUP_RDY	<u>30</u> S	Maximum time, in seconds, specified by vendor from powering on the UUT until it is ready to perform USB functionality. By default this is set to 30 seconds, but a vendor is permitted to specify a longer time.	PI24
TA_WAIT_BCON max	<u> </u> S	The maximum time, in seconds, that V BUS is left on for by an A-device, in the absence of a B-device connecting. The default value is thirty seconds. A vendor is permitted to specify a longer time, but should be aware that this will have an impact on the time taken for, and therefore possibly the cost of, compliance testing.	PI10
Unknown Dev (No HNP)	<u>VID:</u> <u>045E</u> <u>PID:</u> <u>075D</u>	The test will use the VID/PID combination specified during tests for error messages, when an unknown B-device, not capable of HNP, is connected. A default value (1A0A/0201) is used, but any other device not on the UUT's TPL may be defined here.	-



Input	Type	Purpose	Checklist Ref
Unknown Dev (HNP)	<u>VID:</u> <u>1A0A</u> <u>PID:</u> <u>0202</u>	The test will use the VID/PID combination specified during tests for error messages, when an unknown B-device, capable of HNP, is connected. A default value (1A0A/0202) is used, but any other device not on the UUT's TPL may be defined here.	-

Test Cable Information:

Information Obtained From Checklist or Vendor			
Input	Type	Purpose	
Cable A	<u>208</u> m Ω	Test Cable A loop resistance in m Ω .	
Cable B	<u>572</u> m Ω	Test Cable B loop resistance in m Ω .	



High Speed & Basic Speed Compliance Tests

A4.4: Host High-speed Signal Quality

☒ Pass☐ Fail☐ N/A

These tests measure the ability of transmitters to do valid high speed signaling. High speed signal quality is measured on upstream ports. A high speed scope with differential probes is used. Signaling data is captured with the scope and then translated to an eye pattern. The signal quality eye patterns obtained from the measurements must agree with the transmit eye patterns in the USB 2.0 Specification.

Port	01
EL_2: Data Rate	Pass
EL_3: Eye Pattern	Pass
EL_6: Rise and Fall Time	Pass
EL_7: Monotonic	Pass

A4.5: Host Controller Packet Parameters

☒ Pass☐ Fail☐ N/A

This test measures the amount of time it takes hosts and devices to respond. It also verifies Host generated SYNCs and EOPs.

EL_21: (32bit)	32bit/32bit	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_25: (8bit)	8bit	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_23: (>=88bit and <=192bit)	128bit	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_22: (>=8bit and <=192bit)	169bit	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_55: (40bit)	40bit	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A

A4.7: Host CHIRP Timing

☒ Pass☐ Fail☐ N/A

This test examines the basic timings and voltages of both upstream ports during the speed detection protocol. (Device reset from Full Speed)

EL_33: (<=100us)	1.28us	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_34: (>=40us and <=60us)	50.03us	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
EL_35: (100us and <=500us)	356.89us	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A



A4.8: Host Suspend/Resume/Reset timing ☒ Pass ☐ Fail ☐ N/A

This test verifies that a Host can be suspended and resumed while operating in high speed and also that the device can be reset from the suspended state.

EL_39: ☒ Pass ☐ Fail ☐ N/A

EL_41: 112.89us ☒ Pass ☐ Fail ☐ N/A
(≤3ms)

A4.9: Host Test J/K, SE0 NAK (EL_9) ☒ Pass ☐ Fail ☐ N/A

The USB-IF no longer requires EL_8: Test_J and Test_K to be performed as a condition for USB Certification. Measurement of EL_9: Test_J, Test_K and SE0 is still a requirement for certification. EL_9 is defined in the USB 2.0 Test Specification and measures the data line voltage when not driven. For detail information please reference as below link:

EL_9

Port	01
SE0_NAK D+	1.0
SE0_NAK D-	1.0
Test J D-	7.1
Test K D+	7.1

(-20mV to 20mV)

Basic Speed Signal Quality Test Result ☒ Pass ☐ Fail ☐ N/A

Full Speed Downstream Signal Quality: ☒ Pass ☐ Fail ☐ N/A

Port 01
Pass

Low Speed Downstream Signal Quality: ☒ Pass ☐ Fail

Port 01
Pass



Drop/ Droop Test Result

☒ Pass☐ Fail

500mA

Port	01
V _{non-load} ($\geq 4.75V$ and $\leq 5.5V$)	5.197V
V _{load} ($\geq 4.75V$ and $\leq 5.5V$)	5.009V
V _{drop} ($\leq 500mV$)	188mV
V _{droop} ($\leq 330mV$)	N/AmV

BC 1.2 Implemented Check:

☐ Support☒ N/A

If any one of exposed ports has BC 1.2 capability, all items of BC 1.2 specific category(s) should be tested under this port(s) for USB-IF certification.

Port 01
N/A



Embedded Host PET Automated Test (CH 6)

A-UUT

Test Item	Result
6.7.2 A-UUT Initial Power-up Test	Pass
6.7.4 A-UUT V _{BUS} Voltage and Current Measurements	Pass
6.7.5 A-UUT Bypass Capacitance	Pass
6.7.6 A-UUT SRP	Pass
6.7.8 A-UUT ADP	Pass
6.7.9 A-UUT Leakage	Pass
6.7.14 EH, Capable of ADP and SRP, State Transition Test (Standard-A)	N/A
6.7.15 EH, Capable of ADP but not SRP, State Transition Test (Standard-A)	N/A
6.7.16 EH, Capable of SRP but not ADP, State Transition Test (Standard-A)	N/A
6.7.17 EH with no Session Support State Transition Test (Standard-A)	Pass
6.7.18 EH, Capable of ADP and SRP, (Micro-AB) or OTG-A , Capable of ADP and SRP but not HNP, State Transition Test	N/A
6.7.19 EH, Capable of ADP but not SRP, (Micro-AB) or OTG-A , Capable of ADP but not SRP or HNP, State Transition Test	N/A
6.7.20 EH, Capable of SRP but not ADP, (Micro-AB) or OTG-A , Capable of SRP but not ADP or HNP, State Transition Test	N/A
6.7.21 EH with no Session Support State Transition Test (Micro-AB), or OTG-A with no Session or HNP Support	N/A
6.7.22 A-UUT "Device No Response" for connection timeout	Pass
6.7.23 A-UUT "Unsupported Device" Message	Pass
6.7.24 A-UUT "Device No Response" for HNP enable	N/A
6.7.25 EH using Micro-AB "Incorrect Connection"	N/A



B-UUT

Only tested when Embedded Host B-Port is applied

Any B-device compliant with the documentation "On-The-Go and Embedded Host Supplement to the USB Revision 2.0 Specification, Revision 2.0 version 1.1a" shall verify the following B-UUT test items

Test Item	Result
6.8.1 B-UUT Initial Power-up Test	N/A
6.8.2 B-UUT V_{BUS} Voltage and Current Measurements	N/A
6.8.3 B-UUT Bypass Capacitance	N/A
6.8.4 B-UUT SRP	N/A
6.8.6 B-UUT ADP	N/A
6.8.7 B-UUT Leakage	N/A
6.8.13 ADP-Capable Peripheral Only B-device State Transition Test	N/A
6.8.14 SRP Only Capable Peripheral Only B-device State Transition Test	N/A
6.8.15 Peripheral Only B-device, Capable of No Protocols, State Transition Test	N/A
6.8.16 B-UUT "Device no response" for SRP	N/A



Embedded Host Manual Interoperability Tests (CH 7)

This section will perform DUT interoperability with peripheral that on the vendor's Target Peripheral List.

Test Item	Result
7.3.1 A-UUT Functionality B-device	N/A
7.3.2 A-UUT Category Functionality B-device	Pass
7.3.3 A-UUT Boot test	Pass
7.3.4 A-UUT Legacy Speed test	Pass
7.3.5 A-UUT Concurrent and Independently test	N/A
7.3.6 A-UUT Unsupported device Message test	Pass
7.3.7 A-UUT Hub Error message test	N/A
7.3.8 A-UUT Hub Functionality test	Pass
7.3.9 A-UUT Hub maximum tier test	Pass
7.3.10 A-UUT Hub Concurrent and Independent test	Pass
7.3.11 A-UUT Bus powered hub power exceeded test	Pass
7.3.12 A-UUT Maximum concurrently device exceed message test	Pass
7.3.13 A-UUT Standby test	Pass
7.3.14 A-UUT Standby Disconnect test	Pass
7.3.15 A-UUT Standby Attach test	Pass
7.3.16 A-UUT Standby Topology Change test	Pass
7.3.17 A-UUT Standby Remote Wakeup test	N/A



Battery Charging 1.2 Compliance Test

Dedicated Charging Port (DCP)

☐ Pass☐ Fail☒ N/A

Test Items \ Port	Port 01
DCP Overshoot and Undershoot Voltage Test	
DCP Handshaking Test	
DCP Resistance and Capacitance Tests	
DCP Voltage and Current	

Charging Downstream Port (CDP)

☐ Pass☐ Fail☒ N/A

Test Items \ Port	Port 01
CDP Overshoot and Undershoot Voltage Test	
CDP Voltage and Current Test	
CDP Handshaking Test	
CDP Ground Offset Test – Full Speed	
CDP Ground Offset Test – High Speed	

Standard Downstream Port (SDP)

☐ Pass☐ Fail☒ N/A

Test Items \ Port	Port 01
SDP Handshaking Test	



Multiple Role Port (MRP)

☐ Pass

☐ Fail

☒ N/A

Test Items	Port	Port 01
MRP Functional Test		



More Detail Test Result:

1. High Speed Downstream Signal Quality: Pass

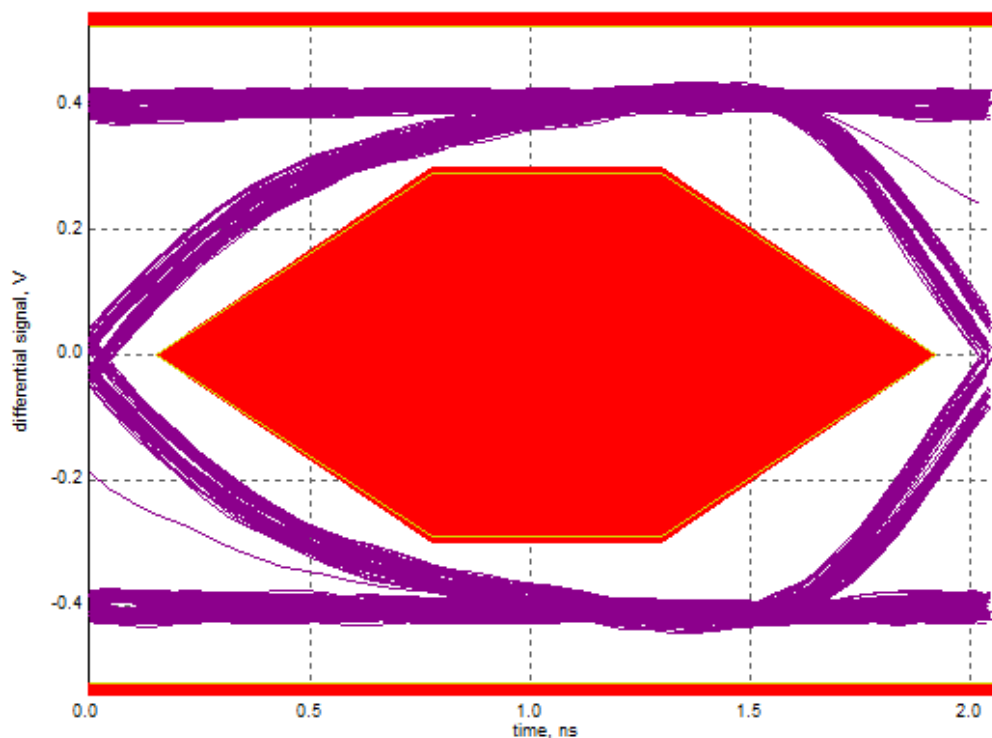
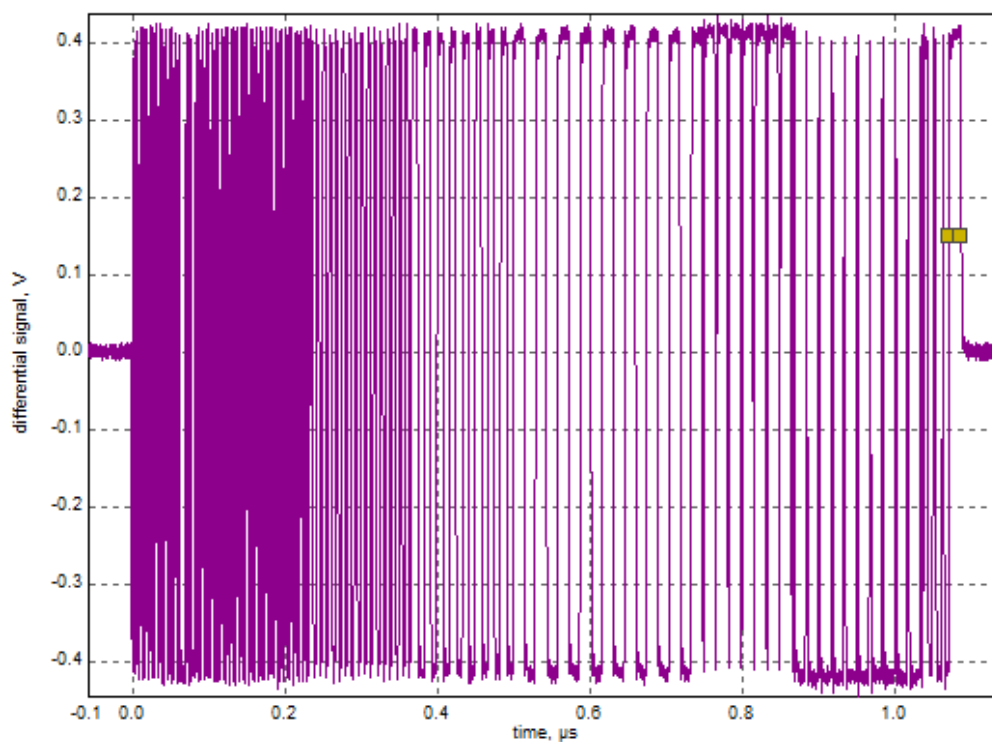
- Overall result: pass!
- Sync result:
sync passes
- Signal eye:
eye passes
- EOP width: 7.97 bits
EOP width passes
- Measured signaling rate: 479.9564 MHz
signal rate passes
- Edge Monotonicity: 0 mV
Monotonic Edge passes
- Rising Edge Rate: 823.65 V/us (777.03 ps equivalent risetime)
passes
- Falling Edge Rate: 829.87 V/us (771.20 ps equivalent falltime)
passes

Additional Information

- Consecutive jitter range: -59.461 ps to 61.730 ps, RMS jitter 28.636 ps
- Paired JK jitter range: -67.929 ps to 75.859 ps, RMS jitter 19.010 ps
- Paired KJ jitter range: -48.687 ps to 55.587 ps, RMS jitter 13.646 ps



SignalData and Eye





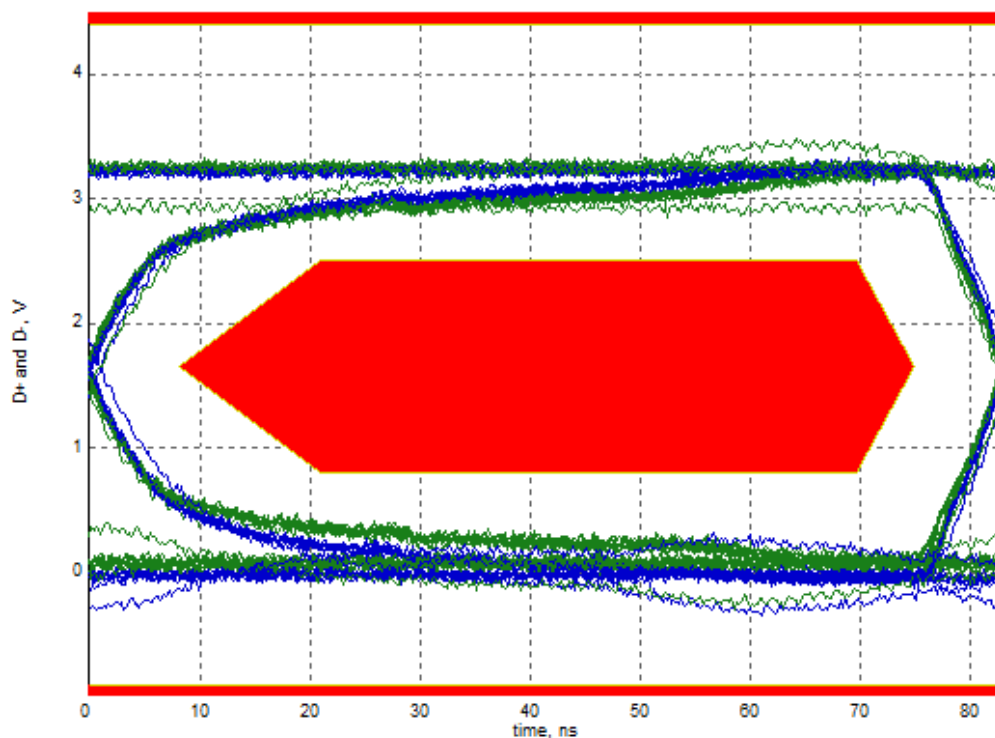
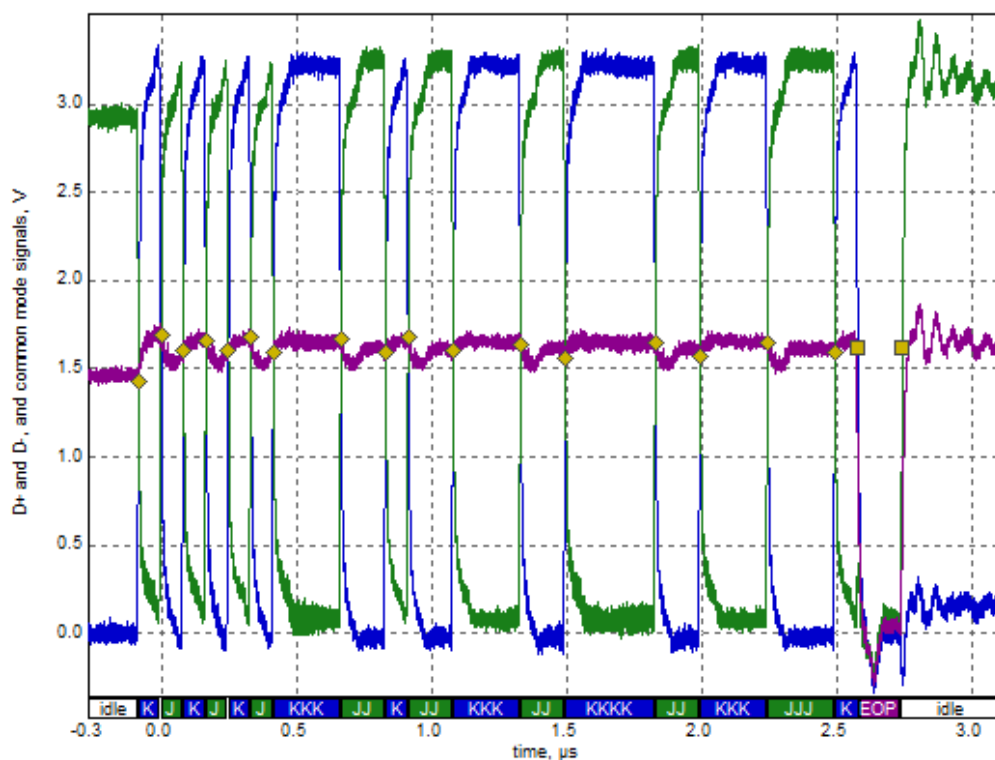
2. Full Speed Downstream Signal Quality: Pass

- Overall result: pass!
- Sync result:
sync passes
- Signal eye:
eye passes
- EOP width: 166.19 ns
EOP width passes
- Measured signaling rate: 11.9979 MHz
signal rate passes
- Edge Monotonicity: 83 mV
Monotonic Edge passes
- Crossover voltage range: 1.43 V to 1.69 V, mean crossover 1.61 V
(first crossover at 1.43 V, 16 other differential crossovers checked)
crossover voltages pass
- Consecutive jitter range: -225.322 ps to 199.634 ps, RMS jitter 145.083 ps
- Paired JK jitter range: -280.821 ps to 124.720 ps, RMS jitter 143.286 ps
- Paired KJ jitter range: -362.094 ps to 318.029 ps, RMS jitter 226.002 ps
jitter passes

Additional Information

- Rising Edge Rate: 186.11 V/us (Equivalent risetime = 14.19 ns)
- Falling Edge Rate: 195.01 V/us (Equivalent falltime = 13.54 ns)
- Edge Rate Match: 4.67% (limit +/-10%)

SignalData and Eye



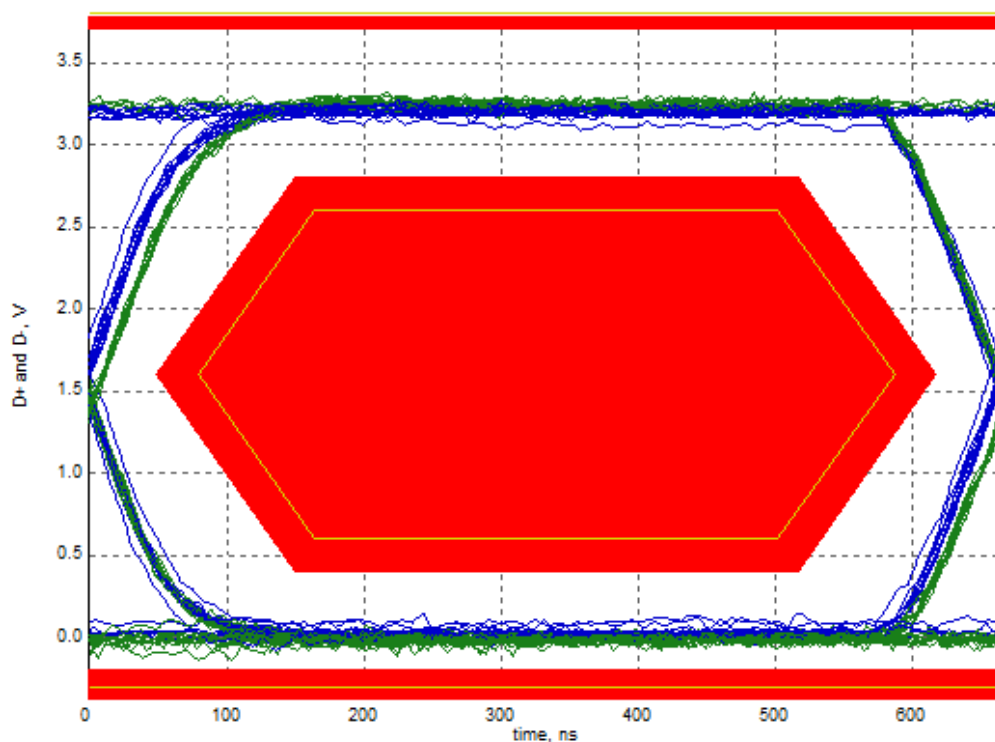
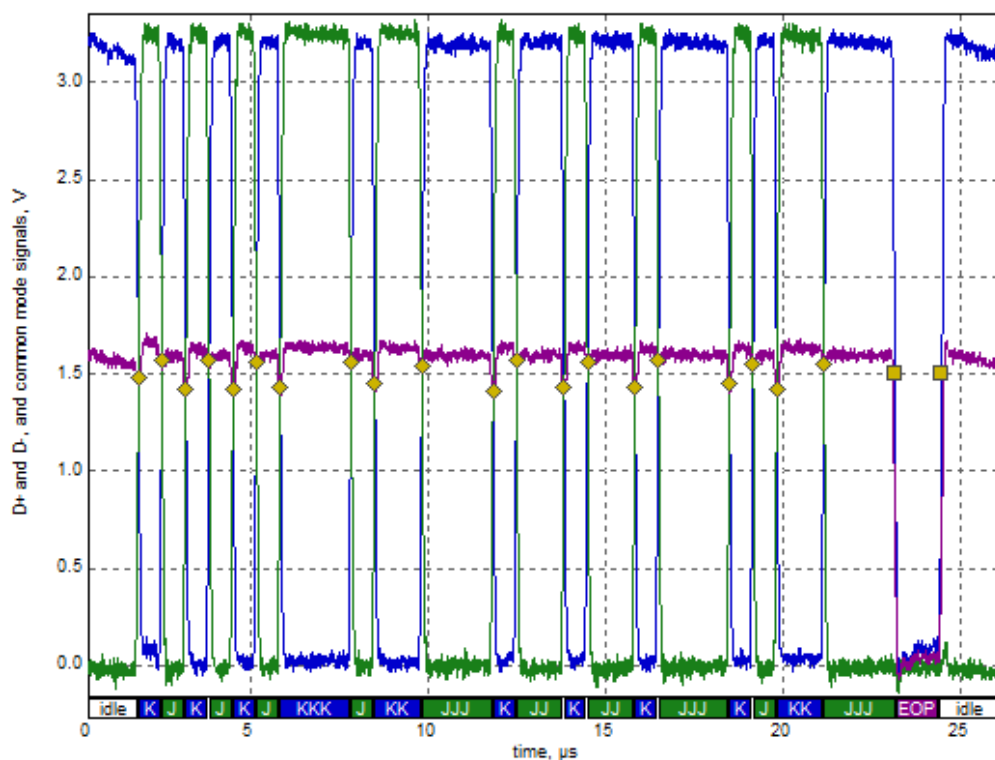


3. Low Speed Downstream Signal Quality: Pass

- Overall result: pass!
- Sync result:
sync passes
- Signal eye:
eye passes
- EOP width: 1.32 us
EOP width passes
- Measured signaling rate: 1.4995 MHz
signal rate passes
- Edge Monotonicity: 0 mV
Monotonic Edge passes
- Crossover voltage range: 1.41 V to 1.57 V, mean crossover 1.50 V
(first crossover at 1.48 V, 19 other differential crossovers checked)
crossover voltages pass
- Consecutive jitter range: -4.474 ns to 4.096 ns, RMS jitter 2.752 ns
- Paired JK jitter range: -0.652 ns to 2.169 ns, RMS jitter 1.046 ns
- Paired KJ jitter range: -0.737 ns to 2.150 ns, RMS jitter 0.978 ns
jitter passes

Additional Information

- Rising Edge Rate: 20.61 V/us (Equivalent risetime = 128.12 ns)
- Falling Edge Rate: 21.31 V/us (Equivalent falltime = 123.89 ns)
- Edge Rate Match: 3.36% (limit +/-20%)



**Test Procedure Reference:**

1. USB On-The-Go and Embedded Host Automated Compliance Plan for the On-The-Go & Embedded Host Supplement Revision 2.0, Version 1.2
2. Universal Serial Bus Implementers Forum High-speed System/Motherboard Compliance Test Procedure, Version: 1.4
3. Universal Serial Bus Implementers Forum Full and Low Speed Electrical and Interoperability Compliance Test Procedure, Version: 1.3
4. USB Battery Charging 1.2 Compliance Plan, Revision: 1.1

Notice: Test result is valid only to the original tested device model. The content of test report may not be copied or re-transmitted (except for the entire report) unless it is prior approved by Allion.